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(communicat\$3 near3 data near3 inspect\$3)	48

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- Derwent World Patents Index
- IBM Technical Disclosure Bulletins

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result set*DB=USPT; PLUR=YES; OP=OR*

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<u>L2</u>	L1 and signal near3 grad\$3 and rat\$3 near3 data	2	<u>L2</u>
<u>L1</u>	(analyz\$3 near3 data) and inspect\$3 near3 data	744	<u>L1</u>

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1. Document ID: US 4764681 A

L2: Entry 1 of 2

File: USPT

Aug 16, 1988

US-PAT-NO: 4764681

DOCUMENT-IDENTIFIER: US 4764681 A

TITLE: Method of and apparatus for electrooptical inspection of articles

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KMC	Drawn D
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2. Document ID: US 4633720 A

L2: Entry 2 of 2

File: USPT

Jan 6, 1987

US-PAT-NO: 4633720

DOCUMENT-IDENTIFIER: US 4633720 A

TITLE: Load monitoring system for progressive dies

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KMC	Drawn D
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Terms	Documents
L1 and signal near3 grad\$3 and rat\$3 near3 data	2

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1. Document ID: US 6665433 B2

L3: Entry 1 of 48

File: USPT

Dec 16, 2003

US-PAT-NO: 6665433

DOCUMENT-IDENTIFIER: US 6665433 B2

TITLE: Automatic X-ray determination of solder joint and view Delta Z values from a laser mapped reference surface for circuit board inspection using X-ray laminography

2. Document ID: US 6654660 B1

L3: Entry 2 of 48

File: USPT

Nov 25, 2003

US-PAT-NO: 6654660

DOCUMENT-IDENTIFIER: US 6654660 B1

TITLE: Controlling thermal expansion of mask substrates by scatterometry

3. Document ID: US 6628817 B2

L3: Entry 3 of 48

File: USPT

Sep 30, 2003

US-PAT-NO: 6628817

DOCUMENT-IDENTIFIER: US 6628817 B2

TITLE: Inspection data analyzing system

4. Document ID: US 6621572 B2

L3: Entry 4 of 48

File: USPT

Sep 16, 2003

US-PAT-NO: 6621572

DOCUMENT-IDENTIFIER: US 6621572 B2
** See image for Certificate of Correction **

TITLE: Optical inspection of laser vias

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Abstract](#) | [Claims](#) | [RQMC](#) | [Draw. D.](#)

5. Document ID: US 6594591 B2

L3: Entry 5 of 48

File: USPT

Jul 15, 2003

US-PAT-NO: 6594591

DOCUMENT-IDENTIFIER: US 6594591 B2

TITLE: Method and system for processing rail inspection test data

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Abstract](#) | [Claims](#) | [RQMC](#) | [Draw. D.](#)

6. Document ID: US 6591207 B2

L3: Entry 6 of 48

File: USPT

Jul 8, 2003

US-PAT-NO: 6591207

DOCUMENT-IDENTIFIER: US 6591207 B2

TITLE: Semiconductor production system

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Abstract](#) | [Claims](#) | [RQMC](#) | [Draw. D.](#)

7. Document ID: US 6529619 B2

L3: Entry 7 of 48

File: USPT

Mar 4, 2003

US-PAT-NO: 6529619

DOCUMENT-IDENTIFIER: US 6529619 B2

TITLE: Inspection data analyzing system

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Abstract](#) | [Claims](#) | [RQMC](#) | [Draw. D.](#)

8. Document ID: US 6522993 B1

L3: Entry 8 of 48

File: USPT

Feb 18, 2003

US-PAT-NO: 6522993

DOCUMENT-IDENTIFIER: US 6522993 B1

TITLE: Method and system for marking surface deviations on a three dimensional surface

Full	Title	Citation	Front	Review	Classification	Date	Reference				Claims	KWIC	Drawn D
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9. Document ID: US 6522247 B2

L3: Entry 9 of 48

File: USPT

Feb 18, 2003

US-PAT-NO: 6522247

DOCUMENT-IDENTIFIER: US 6522247 B2

TITLE: Apparatus monitoring system and apparatus monitoring method

Full	Title	Citation	Front	Review	Classification	Date	Reference				Claims	KWIC	Drawn D
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10. Document ID: US 6501822 B2

L3: Entry 10 of 48

File: USPT

Dec 31, 2002

US-PAT-NO: 6501822

DOCUMENT-IDENTIFIER: US 6501822 B2

TITLE: Z-axis elimination in an X-ray laminography system using image magnification for Z plane adjustment

Full	Title	Citation	Front	Review	Classification	Date	Reference				Claims	KWIC	Drawn D
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11. Document ID: US 6490368 B2

L3: Entry 11 of 48

File: USPT

Dec 3, 2002

US-PAT-NO: 6490368

DOCUMENT-IDENTIFIER: US 6490368 B2

TITLE: Automatic X-ray determination of solder joint and view Delta Z values from a laser mapped reference surface for circuit board inspection using X-ray laminography

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWMC	Drawn D
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12. Document ID: US 6473170 B2

L3: Entry 12 of 48

File: USPT

Oct 29, 2002

US-PAT-NO: 6473170

DOCUMENT-IDENTIFIER: US 6473170 B2

TITLE: Linear optical sensor for a closure

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWMC	Drawn D
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13. Document ID: US 6473169 B1

L3: Entry 13 of 48

File: USPT

Oct 29, 2002

US-PAT-NO: 6473169

DOCUMENT-IDENTIFIER: US 6473169 B1

TITLE: Integrated leak and vision inspection system

Full	Title	Citation	Front	Review	Classification	Date	Reference	Claims	KWMC	Drawn D
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14. Document ID: US 6373917 B1

L3: Entry 14 of 48

File: USPT

Apr 16, 2002

US-PAT-NO: 6373917

DOCUMENT-IDENTIFIER: US 6373917 B1

TITLE: Z-axis elimination in an X-ray laminography system using image magnification for Z plane adjustment

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Abstract](#) | [Claims](#) | [RQMC](#) | [Drawn D.](#)

15. Document ID: US 6339653 B1

L3: Entry 15 of 48

File: USPT

Jan 15, 2002

US-PAT-NO: 6339653

DOCUMENT-IDENTIFIER: US 6339653 B1

TITLE: Inspection data analyzing system

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Abstract](#) | [Claims](#) | [RQMC](#) | [Drawn D.](#)

16. Document ID: US 6330352 B1

L3: Entry 16 of 48

File: USPT

Dec 11, 2001

US-PAT-NO: 6330352

DOCUMENT-IDENTIFIER: US 6330352 B1

TITLE: Inspection data analyzing system

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17. Document ID: US 6324249 B1

L3: Entry 17 of 48

File: USPT

Nov 27, 2001

US-PAT-NO: 6324249

DOCUMENT-IDENTIFIER: US 6324249 B1

TITLE: Electronic planar laminography system and method

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Abstract](#) | [Claims](#) | [RQMC](#) | [Drawn D.](#)

18. Document ID: US 6314201 B1

L3: Entry 18 of 48

File: USPT

Nov 6, 2001

US-PAT-NO: 6314201

DOCUMENT-IDENTIFIER: US 6314201 B1

TITLE: Automatic X-ray determination of solder joint and view delta Z values from a laser mapped reference surface for circuit board inspection using X-ray laminography

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19. Document ID: US 6201850 B1

L3: Entry 19 of 48

File: USPT

Mar 13, 2001

US-PAT-NO: 6201850

DOCUMENT-IDENTIFIER: US 6201850 B1

TITLE: Enhanced thickness calibration and shading correction for automatic X-ray inspection

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Search](#) | [Help](#) | [Claims](#) | [KOMC](#) | [Drawn D](#)

20. Document ID: US 6185322 B1

L3: Entry 20 of 48

File: USPT

Feb 6, 2001

US-PAT-NO: 6185322

DOCUMENT-IDENTIFIER: US 6185322 B1

TITLE: Inspection system and method using separate processors for processing different information regarding a workpiece such as an electronic device

[Full](#) | [Title](#) | [Citation](#) | [Front](#) | [Review](#) | [Classification](#) | [Date](#) | [Reference](#) | [Search](#) | [Help](#) | [Claims](#) | [KOMC](#) | [Drawn D](#)

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